1. UVA DATA 画图: 散点图

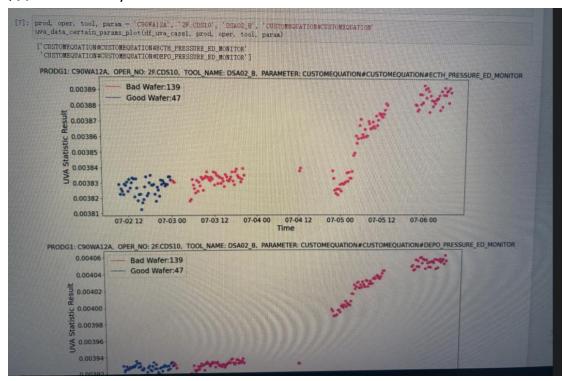
UVA 数据:对每片 WAFER 的 sensor_value,将特定的一段数据(即 STEP)提取,再计算统计值(最常见的统计值是 MEAN, RANGE),也就是将一段数据变成一个值,所以在**给定产品、站点、腔室、参数+STEP下,每一片 WAFER**只有一个值。

```
In [1]: import varnings

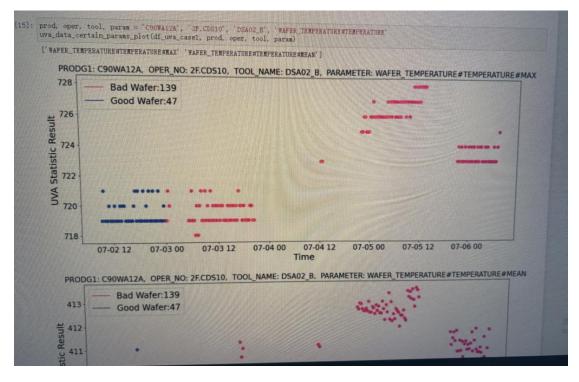
varnings.filtervarnings('ignore')

import datetine
import pardse as pd
import name as pd
import name as pd
import attetine
import att
```

例子1: customequation



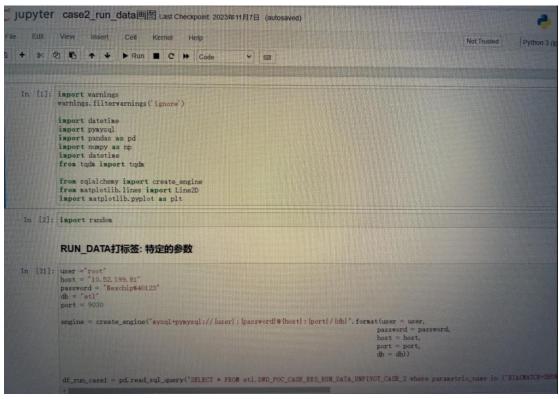
例子 2:在产品为 C90WA12A,站点为 2F.CDS10,腔室为 DSA02_B,参数为 WAFER_TEMPERATURE,STEP 信息为 TEMPERATURE 中,分别提取了 MEAN 和 MAX 两种统计值,所以在 7 月 2 日——7 月 6 日之间的 UVA 对应两幅图:



2. RUN DATA 下钻画图:时间趋势图

支持选取特定数量的 g/b,支持选取特定参数取值范围内进行画图,要灵活

RUN DATA: 对每片 WAFER 的 sensor_value,对同一个 parametric_name 按照时间先后排序,每片 WAFER 在该时间段内的此参数是一条随着时间变化的曲线。所以在给定产品、站点、腔室、参数下,每一片 WAFER 是一条曲线。横轴是 Time Index(时间从小到大进行排序后,再从 1 开始计数),因为 good wafer 和 bad wafer 可能会在不同时间段内有参数值,按照真实时间去画图会导致曲线"压缩",导致看不出真实的 good 和 bad 的 RUN DATA 差异。



```
In [35]: def assign_label(row):
    if row['waFER_ID'] in good_vafer:
    return 0
    elif row['waFER_ID'] in bad_vafer:
    return 'NOP'

In [36]: df_rum_casel['label'] = df_rum_casel.apply(assign_label, aris=1)

In [37]: df_rum_casel.shape

Out[37]: (1894419, 20)

In [38]: df_rum_casel['label'].value_counts()

Out[38]: 0 1027898
    1 840092
    NOP 20429
    Nane: label, dtype: int04

In [39]: df_rum_casel = df_rum_casel['df_rum_casel['label'] = 'NOP')], reset_index(drop=True)
    df_rum_casel.shape

Out[39]: (1867990, 20)

In [40]: print(df_rum_casel[df_rum_casel['label'] = 1]['WaFFE_ID'].numique())
    print(df_rum_casel[df_rum_casel['label'] = 0]['WaFFE_ID'].numique())

print(df_rum_casel[df_rum_casel['label'] = 0]['WaFFE_ID'].numique())

188
    388
```

```
In [23]: # df_rum_case_uwa = df_rum_casei(df_rum_casei('VAFER_ID').isin(uwa_wafer)).reset_index(drop=Irue)
# df_rum_case_uwa
    In [43]: df_run_case_uva = df_run_case1
  In [44]: print("数据维度是: ", df_run_case_uwa.shape)
print("PRODGI是: ", df_run_case_uwa["PRODGI"].unique())
print("TOOL_RAMEE: ", df_run_case_uwa["TOOL_NAME"].unique())
print("OPER_NO便: ", df_run_case_uwa["OPER_NO"].unique())
print("parametric_name#: ", df_run_case_uwa["parametric_name"].unique())
                         教服性质量: (1867990, 20)
PRODCI量: ['C90WA14A' 'C90WA11A' 'C90WA12A' 'C90WA20A' 'C90WA07P' 'C90WA15A']
TOOL_MARE是: ['DSA02_C' 'DSA02_B' 'DSA02_A']
OPER_MO是: ['2F.CDSIO]

PATABATCH-SHUNT+SET 'BUFFER-FORELINE-PRESSURE' 'NF3+SIDE-PRESSURE' 'BIASMATCH-SERIES+SET'
'BIASMATCH-SHUNT+SET' 'BUFFER-PRESSURE' 'NF3+CLN+PRESSURE']
[26]: def run_data_trace_plot(df, prod, oper, tool, param, value_range='all', vafer_num='all'):
                     # 香花用一个組合下程的效理

df_certain_param = (df,query('PRODG: = '[]' & OPER_NO = '[]' & TOOL_NAME = '[]' & purametric_name = '[]

.format(prod, oper, tool, param))[['WAFER_ID', 'OPER_NO', 'TOOL_NAME', 'PRODG!

'TIME_STAMP', 'parametric_name', 'sensor_value', ']
                     'TIME_STAMP', 'parametric_name', 'sensor_value', 'label']]
.reset_index(drop=True)

df_certain_param['TIME_STAMP'] = pd. to_datetime(df_certain_param['TIME_STAMP'], infer_datetime_format=True, format='%YMAMA')

df_certain_param['sensor_value'] = df_certain_param['sensor_value'].astype(float)
                           根据给定的value_range抽取对应的数据
                     if value_range == 'all':
df_certain_param = df_certain_param
                     else:

df_certain_param = df_certain_param.query(value_range)
                     # 機器wafer_mum. 在good和bad中分別抽取对定数量的数据
if wafer_mum == 'all';
df_certain_param = df_certain_param
```

else:

labell_data = df_certain_param[df_certain_param['label'] == 1]
label0_data = df_certain_param[df_certain_param['label'] == 0]

df_certain_param = selected_data

selected wafer label1 = random.saaple(label1_data['VAFER_ID'].unique().tolist(), wafer_num)
selected_wafer_label0 = random.saaple(label0_data['WAFER_ID'].unique().tolist(), wafer_num)
selected_data = pd.concat([label1_data[label1_data['WAFER_ID']].inif(selected_wafer_label1)],
label0_data[label0_data['WAFER_ID']].isin(selected_wafer_label0]]))

```
legend_elements = [
LineZD([0], [0], color='deeppink', label=f'Ead Wafer: [df_certain_param[df_certain_param['label'] == 1]['WAFER_ID'].mmique()['),
LineZD([0], [0], color='royalblue', label=f'Good Wafer: [df_certain_param[df_certain_param['label'] == 0]['WAFER_ID'].mmique()[')
# EM # H. #CF#EE

plt.figure(figsize=(16, 6))

grouped = df_certain_param.groupby('WAFER_ID')

for name, group in grouped:

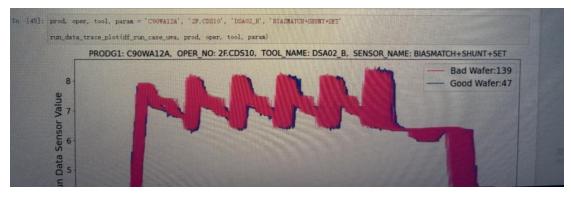
grp = group.sort_values('TIME_STAMP').reset_index(drop=True)

color = 'deeppink' if grp['label'].iloc[0] = 1 else 'royalblue'

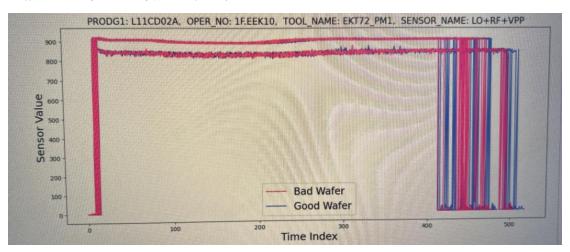
linewidth = 1 if grp['label'].iloc[0] == 1 else 3

alpha = 0.5 if grp['label'].iloc[0] == 1 else 1
          plt.plot(grp['sensor_value'], color=color, linewidth=linewidth, alpha=alpha)
plt.xlabel("Time Index", size=18)
plt.xticks(size=15)
plt.ylabel("Run Data Sensor Value", size=18)
plt.yticks(size=15)
plt.legend(handles=legend_elements, fontsize='xx-large')
 plt.legend(handles=legend_elements, fontsize='xx-large')
plt.title("PRODG1: [], OPER_NO: [], TOOL_NAME: [], SENSOR_NAME: []", format(prod, oper, tool, param), size=15)
plt.show()
```

例: 在产品为 C90WA12A, 站点为 2F.CDS10, 腔室为 DSA02_B, 参数为 BIASMATCH+SHUNT+SET, 所有 WAFER 在特定时间段内的曲线图



例:在产品为 L11CD02A,站点为 1F.EEK10,腔室为 EKT72_PM1,参数为 LO+RF+VPP, 所有 WAFER 在特定时间段内的曲线图



可以观察到有很多"毛刺"的地方聚焦在 Sensor Value>=800,按照相同的条件,只画出 Sensor Value>=800 的图:

